Reexamination CHOU ET AL. 10/768,069 Notice of References Cited Art Unit Examiner Page 1 of 1

Application/Control No.

2818 David Nhu

Applicant(s)/Patent Under

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,716,757 B2	04-2004	Lin et al.	438/705
	В	US-6,426,254 B2	07-2002	Kudelka et al.	438/246
	С	US-6,194,755 B1	02-2001	Gambino et al.	257/301
	D	US-6018174	01-2000	Schrems et al	257/296
	E	US-6071823	06-2000	Hung et al	438/714
	F	US-5837612	11-1998	Ajuria et al	438/697
	G	US-6232171 B1	05-2001	Mei	438/246
	Н	US-			
	_	US-			
	7	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	v	
	w	
	х	

A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.